

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination KIM, EUNG-SUN	
		Examiner DANIEL TEKLE	Art Unit 2621	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0118321	06-2003	Sparrell et al.	386/68
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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